TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (U-MOS II)

TPC8209

Lithium Ion Battery Applications
Portable Equipment Applications
Notebook PC Applications

- Small footprint due to small and thin package
- Low drain-source ON resistance: $RDS(ON) = 30 \text{ m}\Omega \text{ (typ.)}$
- High forward transfer admittance: $|Y_{fs}| = 10 \text{ S (typ.)}$
- Low leakage current: $I_{DSS} = 10 \mu A \text{ (max) (V}_{DS} = 30 \text{ V)}$
- Enhancement-mode: $V_{th} = 1.3 \text{ to } 2.5 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

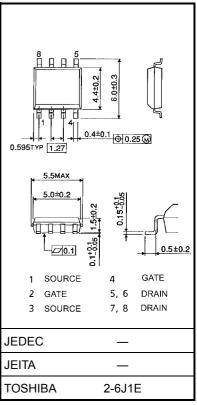
Maximum Ratings (Ta = 25°C)

Char	racteristics	Symbol	Rating	Unit	
Drain-source vol	tage	V _{DSS}	30	V	
Drain-gate voltag	ge (R _{GS} = 20 kΩ)	V_{DGR}	30	V	
Gate-source volt	age	V _{GSS}	±20	V	
Drain current	D C (Note 1)	I _D	5	Α	
Drain current	Pulse (Note 1)	I _{DP}	20	A	
Drain power dissipation	Single-device operation (Note 3a)	P _{D (1)}	1.5	W	
(t = 10s) (Note 2a)	Single-device value at dual operation (Note 3b)	P _{D(2)}	1.1		
Drain power dissipation (t = 10s) (Note 2b)	Single-device operation (Note 3a)	P _{D (1)}	0.75	W	
	Single-device value at dual operation (Note 3b)	P _{D (2)}	0.45		
Single pulse ava	lanche energy (Note 4)	E _{AS}	32.5	mJ	
Avalanche curre	nt	I _{AR}	5	Α	
Repetitive avalar Single-device va	nche energy lue at dual operation (Note 2a, 3b, 5)	E _{AR}	0.1	mJ	
Channel tempera	ature	T _{ch}	150	°C	
Storage tempera	ture range	T _{stg}	-55~150	°C	

Note: For (Note 1), (Note 2), (Note 3) and (Note 4), please refer to the next page.

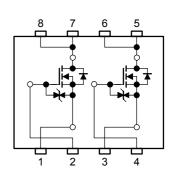
This transistor is an electrostatic sensitive device. Please handle with caution.

Unit: mm



Weight: 0.08 g (typ.)

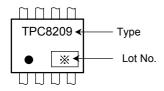
Circuit Configuration



Thermal Characteristics

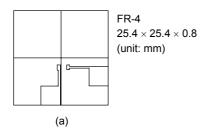
Characteristics	Symbol	Max	Unit		
Thermal resistance shannel to embient	Single-device operation (Note 2a)	R _{th (ch-a) (1)}	83.3	°C/W	
Thermal resistance, channel to ambient (t = 10s) (Note 1a)	Single-device value at dual operation (Note 2b)	R _{th (ch-a) (2)}	114		
Thermal resistance, channel to ambient	Single-device operation (Note 2a)	R _{th (ch-a) (1)}	167		
(t = 10s) (Note 2b)	Single-device value at dual operation (Note 2b)	R _{th (ch-a) (2)}	278		

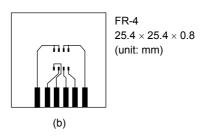
Marking (Note 6)



Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2:





- a) Device mounted on a glass-epoxy board (a)
- b) Device mounted on a glass-epoxy board (b)

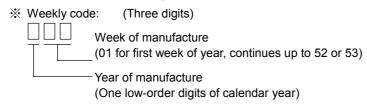
Note 3:

- a) The power dissipation and thermal resistance values are shown for a single device. (During single-device operation, power is only applied to one device.)
- b) The power dissipation and thermal resistance values are shown for a single device. (During dual operation, power is evenly applied to both devices.)

Note 4: V_{DD} = 24 V, T_{ch} = 25°C (initial), L = 1.0 mH, R_G = 25 Ω , I_{AR} = 5 A

Note 5: Repetitive rating: pulse width limited by maximum channel temperature

Note 6: • on lower left of the marking indicates Pin 1.



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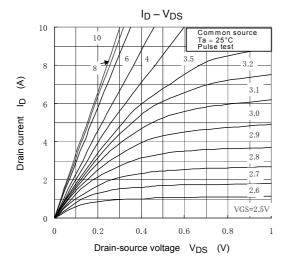
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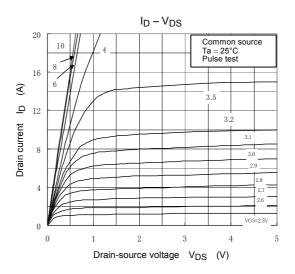
Electrical Characteristics (Ta = 25°C)

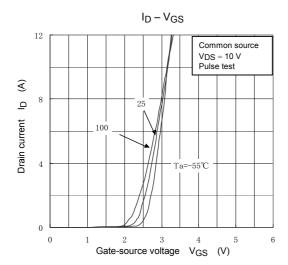
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V	_	_	±10	μΑ
Drain cut-OFF curren	t	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V	_	_	10	μΑ
Drain-source breakdo	wn voltage	V _{(BR) DSS}	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$ 30	30	_	_	V
Drain-source breakdown voltage		V _{(BR) DSS}	I_D = 10 mA, V_{GS} = -20 V	15		_	V
Gate threshold voltage	е	V_{th}	V _{DS} = 10 V, I _D = 1 mA	1.3	_	2.5	V
Drain-source ON resi	etaneo	R _{DS (ON)}	V _{GS} = 4.0 V, I _D = 2.5 A	_	43	60	mO.
Drain-source ON resistance		R _{DS (ON)}	V _{GS} = 10 V, I _D = 2.5 A	_	30	40	mΩ
Forward transfer admittance		Y _{fs}	V _{DS} = 10 V, I _D = 2.5 A	5	10	_	S
Input capacitance		C _{iss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	600	_	pF
Reverse transfer capacitance		C _{rss}		_	95	_	
Output capacitance		Coss		_	160	_	
Switching time	Rise time	tr	$V_{GS} \stackrel{10 \text{ V}}{\text{0 V}} \stackrel{\text{I}_{D} = 2.5 \text{ A}}{\text{0 V}} \stackrel{\text{O}}{\text{OUT}} \stackrel{\text{O}}{\text{C}} \stackrel{\text{O}}{\text{C}} \stackrel{\text{O}}{\text{U}} \stackrel{\text{O}}{\text$	_	4	_	
	Turn-ON time	t _{on}		_	10	_	ns
	Fall time	t _f		_	9	_	115
	Turn-OFF time	t _{off}	Duty ≦ 1%, t _W = 10 μs	_	35	_	
Total gate charge (Gate-source plus gate-drain)		Q_{g}	V _{DD} ≈ 24 V, V _{GS} = 10 V, I _D = 5 A	_	15	_	
Gate-source charge		Q_{gs}		_	11	_	nC
Gate-drain ("miller") charge		Q_{gd}		_	4	_	

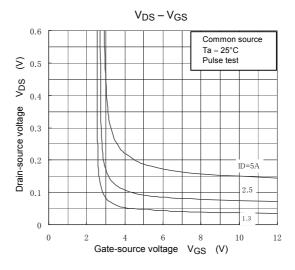
Source-Drain Ratings and Characteristics (Ta = 25°C)

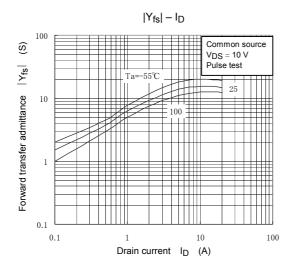
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I _{DRP}	_	_	_	20	Α
Forward voltage (diode)		V _{DSF}	I _{DR} = 5 A, V _{GS} = 0 V		_	-1.2	V

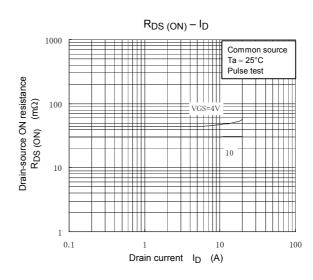


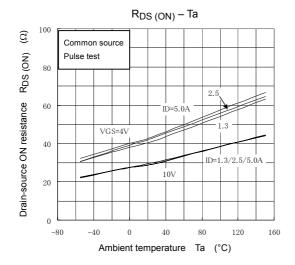


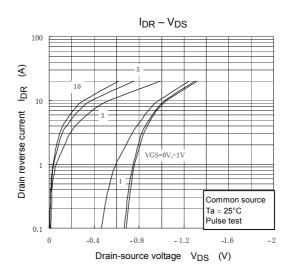


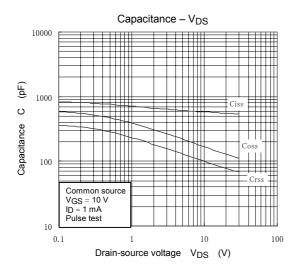


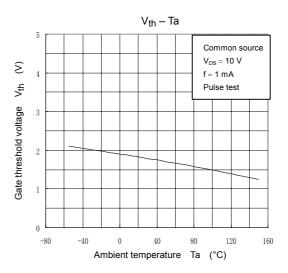


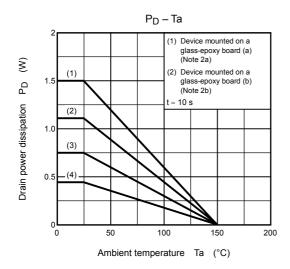


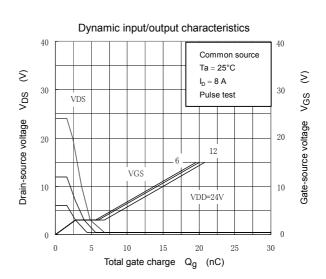


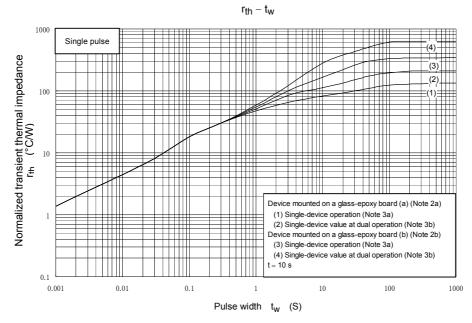




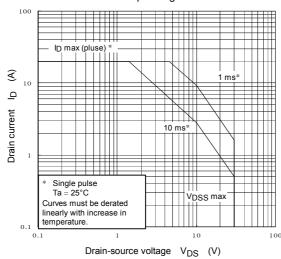












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